

<b>Notice of References Cited</b>	Application/Control No. 10/617,690	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	U.S. Patent Application No. 2004/0162036 (Park), 08-2004
	V	U.S. Patent Application No. 2003/0155216 (Park et al.), 08-2003
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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